Miniature 6-axis force torque sensor MMS101 Data Sheet

DESCRIPTION



This is a 6-axis force torque sensor which has 3-axis force and 3-axis moment. It has a hybrid structure of a MEMS chip and a metal structure, realizing 6-axis detection. This product has AFE ICs built in its module and produces digital output (SPI). Correction coefficients used for matrix operation (other axis interference components are removed) are stored in memories inside the AFE ICs. Since they can be read out immediately before the measurement start, users do not have to control the sensor and the correction coefficients. Additionally, the LDO built in the module reduces noises. This product is extremely small and light, suitable for fingertips of robot hands.

FEATURES

· Very small: Φ 9.6(W) × 9.0(H) mm

· Light weight: 3 g

• High load capacity Fx, Fy, Fz:200N / Mx, My, Mz:1.8N•m

Load rating Fx, Fy, Fz:40N / Mx, My, Mz:0.4N·m

Noise reduction by built-in LDO

Fx, Fy: 0.04N RMS / Fz: 0.06N RMS

Mx, My:0.0004N m RMS / Mz:0.0008N m RMS

Digital output of 6-axis data by built-in sequencer (SPI)

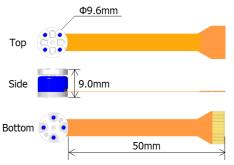


Fig. 1 Product appearance

SAMPLE MODEL NUMBER

MMS101-C3S

**Before installing and using this product, please carefully read "PRECAUTIONS FOR SENSOR

INSTALLATION" and "PRECAUTIONS FOR SENSOR HANDLE" in this document. Otherwise, incorrect installation may cause damage to this product.

**The content of the content

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BLOCK DIAGRAM

This product has six AFEs corresponding to each axis. Please switch CSB pin voltage level to access each AFE for operation.

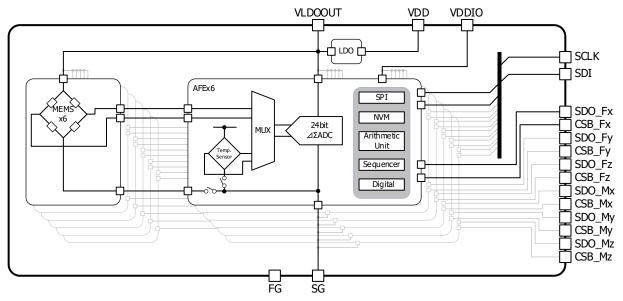
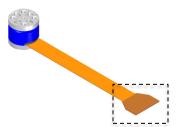


Fig. 2 Block Diagram

PIN CONFIGURATION



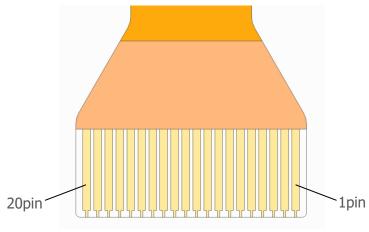


Fig. 3 Pin configuration

*The terminal are located on the back of the FPC.
The above finger is a perspective view.

TERMINAL EXPLANATIONS

Table 1 Pin table

No.	Pin Name	Туре	Function
1	FG	-	Frame ground
2	FG	-	Frame ground
3	CSB_Fz	Ι	AFE3(Fz) Chip select for SPI communication (negative logic)
4	SDO_Fz	0	AFE3(Fz) Serial Data Output for SPI communication
5	CSB_Mz	I	AFE6(Mz) Chip select for SPI communication (negative logic)
6	SDO_Mz	0	AFE6(Mz) Serial Data Output for SPI communication
7	CSB_Mx	Ι	AFE4(Mx) Chip select for SPI communication (negative logic)
8	CSB_My	Ι	AFE5(My) Chip select for SPI communication (negative logic)
9	VDDIO	I	Digital I/O power supply
10	VLDOOUT	0	Built-in LDO output * Not-in-use during normal operation. However, it is recommended to connect a capacitor (10uF) near the sensor connection cable connector on your circuit board for noise reduction.
11	VDD	Ι	Analog power supply
12	SG	-	Signal ground
13	CSB_Fx	Ι	AFE1(Fx) Serial Data Output for SPI communication
14	SCLK	I	Serial clock for SPI communication
15	SDO_Fy	0	AFE2(Fy) Serial Data Output for SPI communication
16	SDI	Ι	Serial Data Input for SPI communication
17	SDO_My	0	AFE5(My) Serial Data Output for SPI communication
18	SDO_Fx	0	AFE1(Fx) Serial Data Output for SPI communication
19	SDO_Mx	0	AFE4(Mx) Serial Data Output for SPI communication
20	CSB_Fy	Ι	AFE2(Fy) Chip select for SPI communication (negative logic)

ABSOLUTE MAXIMUM RATINGS

(unless otherwise specified, $Ta = 25^{\circ}$ C)

Item	Symbol	Min.	Max.	Unit
Load capacity	F _{MAX}	-200	200	N
Load Capacity	M_{MAX}	-1.8	1.8	N•m
Storage temperature range	T _{STG}	-10	+60	$^{\circ}$
Analog supply voltage	VDD _{MAX}	-0.3	+15	V
Digital I/O voltage	VDDIO _{MAX}	-0.3	+4.0	V

RECOMMENDED OPERATING CONDITIONS

(unless otherwise specified, $Ta = 25^{\circ}C$)

Item	Symbol	Min.	Max.	Unit
Load rating	Fopr	-40	40	N
Load rading	Mopr	-0.4	0.4	N•m
Operating temperature range	Topr	+5	+45	$^{\circ}$
Analog supply voltage	VDDopr	+3.8	+14	V
Digital I/O voltage	VDDIO _{OPR}	+1.14	+3.6	V

Power-on sequence

There is no specification for the power-on sequence of both VDD and VDDIO supplies. When the power is turned on, access the device at least 10msec after both VDD and VDDIO supplies have reached 90% of the applied voltage.

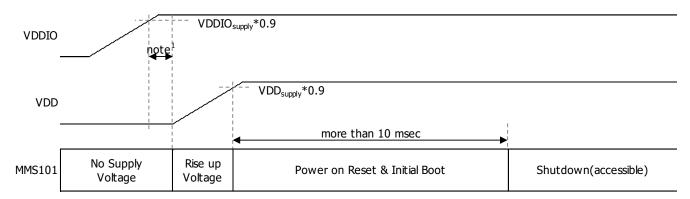


Fig. 4 Power-on sequence

note¹: No time is specified from starting VDDIO to input VDD. There is no problem even if the power-on sequence of both VDD and VDDIO supplies is reversed.

FORCE TORQUE SENSOR CHARACTERISTICS

(unless otherwise specified, Ta = 25°C, VDD = 3.8 to 14 V, VDDIO = 1.14 to 3.6 V)

Iter		Symbol	Condition	Min.	Тур.	Max.	Unit.
Theoretical FxF	FxFyFz	F _{RES}	-	-	0.001	-	N
resolution	MxMyMz	M _{RES}	-	-	0.00001	-	N•m
	FxFy	F _{Eresxy}	-	-	0.04	-	N RMS
Effective resolution	Fz	F _{Eresz}	-	-	0.06	-	N RMS
(note ²)	MxMy	M _{Eresxy}	-	-	0.0004	-	N∙m RMS
	Mz	M _{Eresz}	-	-	0.0008	-	N∙m RMS
Linea (note	,	F _L M _L	FS=40N or 0.4N·m	-1.0	-	1.0	%FS
Hyster	resis	F _{Hys} M _{Hys}	FS=40N or 0.4N·m	-1.0	-	1.0	%FS
Accur (note	,	F _{Acc} M _{Acc}	FS=40N or 0.4N·m	-5.0	-	5.0	%FS
Conversion	on time	t _{con}	-	-	781.25	-	usec
Later	ncy	t _{lat}	Conversion time: Typ. Communication clock: 1MHz No delay in switching of AFE to access	-	-	2.0	msec

note²: The values in chart are the results of the measurement using our evaluation equipment and board.

Definition of Force Torque Sensor Characteristics

· Full Scale FS

Full-scale FS is 40N or 0.4N·m from zero to the load rating for positive and negative.

· Theoretical resolution

The value is equivalent to 1LSB of output data.

· Effective resolution

Standard deviation of 500-point data acquired after measurement is started with no load and the output is stabled.

Linearity

Deviation from Reference line connecting the output between no load state and +40N (0.4N·m) applied state or -40 N (0.4N·m) applied state.

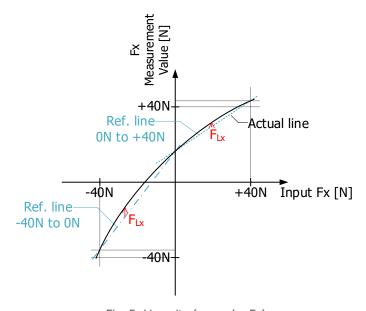


Fig. 5 Linearity (example: Fx)

· Hysteresis

Change amount from the origin after one cycle of continuous application of the load ratings ($\pm 40N$ (0.4N·m)).

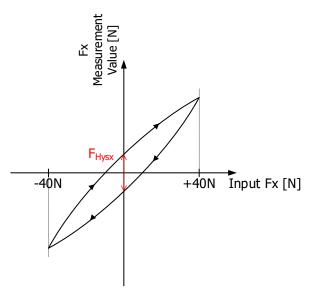


Fig. 6 Hysteresis (example: Fx)

Accuracy

Deviation of the applied load and output when a load is applied to the main axis while the offset output in the unloaded state is canceled.

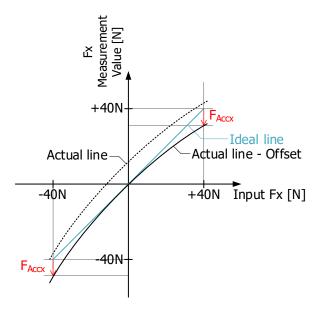


Fig. 7 Accuracy (example: Fx)

- Conversion time
 Update interval of ADC data output from each AFE
- Latency
 Delay time from the timing of output data measurement to the timing of matrix operation completion.

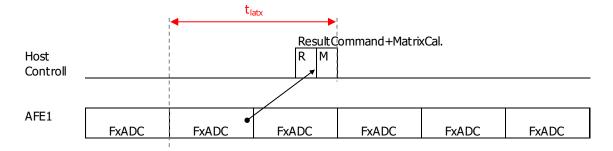


Fig. 8 Latency (example: Fx)

ELECTRICAL CHARACTERISTICS

Analog Characteristics

(unless otherwise specified, Ta = 25°C, VDD = 4.3 V, VDDIO = 3.3 V)

Item	Symbol	Condition	Min.	Тур.	Max.	Unit.
VDD Current consumption	I_{VDDact}	Measure active	-	-	10	mA
VDDIO Current consumption	I _{VDDIOact}	Measure active	-	-	20	uA

Digital I/O Characteristics

(unless otherwise specified, Ta = 25°C, VDD = 3.8 to 14 V, VDDIO = 1.14 to 3.6 V)

Item	Symbol	Condition	Min.	Тур.	Max.	Unit
High level Input voltage	V _{IH}	-	0.8 × VDDIO	-	VDDIO + 0.3	V
Low level Input voltage	V_{IL}	-	-0.3	-	0.2 × VDDIO	V
Output voltage High level	V _{OH1}	VDDIO ≥ 2.0V, Iload = -3mA	VDDIO - 0.4	1	1	٧
	V _{OH2}	VDDIO < 2.0V, $Iload = -1mA$	0.8 × VDDIO	-	-	V
Output voltage	V _{OL1}	VDDIO ≥ 2.0V, Iload = 3mA	-	-	0.4	V
Low level	V _{OL2}	VDDIO < 2.0V, Iload = 1mA	-	-	0.2 × VDDIO	V

FUNCTION

Operation Description

MMS101 can acquire data following the operation flow shown below.

Correction coefficients used in the matrix operation are stored in the memory (NVM: Non-Volatile Memory) built in each AFE. Reading out the correction coefficients before issuance of measurement start instruction allows the matrix operation after ADC data of each axis is acquired.

ADC data offset changes depending on ambient temperature. If needed, temperature sensor values used for offset correction arithmetic done in each AFE should be updated at any timing.

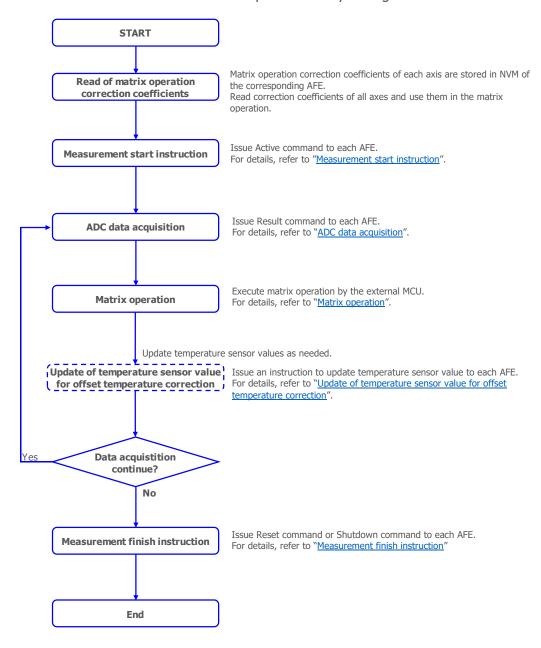


Fig. 9 Operation flow chart

Read of matrix operation correction coefficients

Matrix operation correction coefficients are stored in the memory (NVM: Non-Volatile Memory) built in each AFE. Please read the matrix operation correction coefficient 1 to 6 (3 bytes / 24 bits) shown in Table 3 from all AFEs. These coefficients can be read by executing NVM read command. To execute this command, AFEs must be in the Idle state. Therefore, Idle command must be issued and executed in advance. For command code and format, refer to "COMMAND CODE" and "SPI format".

Table 2 NVM map of matrix operation correction coefficients

NVM Addr.	Table 2 NVPI IIIap of IIIa	·			ration form	ula (note³)	
NVM Addi.		AFE1	AFE2	AFE3	AFE4	AFE5	AFE6
5Ah	MSB						
5Bh	Matrix operation correction coefficient 1	A1	B1	C1	D1	E1	F1
5Ch	LSB						
5Dh	MSB						
5Eh	Matrix operation correction coefficient 2	A2	B2	C2	D2	E2	F2
5Fh	LSB						
60h	MSB						
61h	Matrix operation correction coefficient 3	A3	В3	C3	D3	E3	F3
62h	LSB						
63h-6Bh	For Manufacturer						
6Ch	MSB						
6Dh	Matrix operation correction coefficient 4	A4	B4	C4	D4	E4	F4
6Eh	LSB						
6Fh	MSB						
70h	Matrix operation correction coefficient 5	A5	B5	C5	D5	E5	F5
71h	LSB						
72h	MSB						
73h	Matrix operation correction coefficient 6	A6	В6	C6	D6	E6	F6
74h	LSB						

note³: For details of matrix operation formula, refer to "Matrix operation".

Measurement start instruction

Each AFE starts AD conversion when receiving Active command. For command code and format, refer to "COMMAND CODE" and "SPI format". Fig. 10 schematically shows an example of AD conversion start instruction issued to AFE1. This instruction must be issued to all AFEs because matrix operation uses ADC data of all axes.

ADC data is subject to offset temperature correction in each AFE. Approximately 5 msec is required to complete the first AD conversion because of temperature sensor measurement for offset temperature correction and waiting for filter stabilization. From the second AD conversion, the conversion is repeated at the interval of approximately 0.8 msec because neither the temperature sensor measurement nor waiting for filter stabilization is required.

Drift occurs in Fz (AFE3) immediately after the AD conversion start. In this case, it is recommended that data is acquired after waiting approximately 5 min for stabilization.

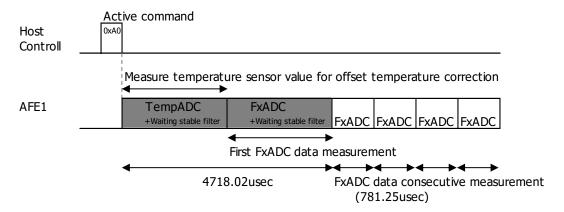


Fig. 10 Schematic of AD conversion start instruction

The second and subsequent ADC data are subject to offset temperature correction using temperature sensor values acquired during the initial AD conversion. This makes correction error larger with changes in ambient temperature, requiring regular update of the temperature sensor values. For update of temperature sensor values, refer to "Update of temperature sensor value for offset temperature correction".

ADC data acquisition

To acquire ADC data (3 bytes / 24 bits), Result command should be issued to each AFE. For command code and format, refer to "COMMAND CODE" and "SPI format". Fig. 11 schematically shows an example of ADC data acquisition from AFE1. Result command must be issued to all AFEs to acquire ADC data of all axes because matrix operation uses this data.

Each AFE returns the last AD-converted data when receiving Result command. If Result command is issued during the first AD conversion, ADC data will be 000000 h.

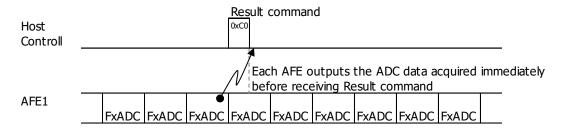


Fig. 11 Schematic of ADC data acquisition

Matrix operation

Please execute the matrix operation below by an external MCU, using matrix operation correction coefficients (3 bytes / 24 bits) and ADC data (3 bytes / 24 bits).

Matrix operation formula (note³)

$$\begin{pmatrix} A1 & A2 & A3 & A4 & A5 & A6 \\ B1 & B2 & B3 & B4 & B5 & B6 \\ C1 & C2 & C3 & C4 & C5 & C6 \\ D1 & D2 & D3 & D4 & D5 & D6 \\ E1 & E2 & E3 & E4 & E5 & E6 \\ F1 & F2 & F3 & F4 & F5 & F6 \end{pmatrix} \begin{pmatrix} FxADC \\ FyADC \\ FzADC \\ MxADC \\ MyADC \\ MzADC \end{pmatrix} = \begin{pmatrix} FxMD \\ FyMD \\ FzMD \\ MxMD \\ MyMD \\ MzMD \end{pmatrix}$$

Matrix operation correction coefficients (3 bytes / 24 bits)

ADC data (3 bytes / 24 bits) Matrix operation data (Input range equal to or less than load capacity => Max. 4 bytes / 32 bits)

Matrix operation data FxMD to MxMD should be right-shifted by 11 bits to convert the force into 0.001*N and the moment into 0.00001*N·m.

 $\begin{aligned} & \text{Fx} = \text{FxMD} \div 2^{11} \text{ [0.001*N]} \\ & \text{Fy} = \text{FyMD} \div 2^{11} \text{ [0.001*N]} \\ & \text{Fz} = \text{FzMD} \div 2^{11} \text{ [0.001*N]} \\ & \text{Mx} = \text{MxMD} \div 2^{11} \text{ [0.00001*N·m]} \\ & \text{My} = \text{MyMD} \div 2^{11} \text{ [0.00001*N·m]} \\ & \text{Mz} = \text{MzMD} \div 2^{11} \text{ [0.00001*N·m]} \end{aligned}$

note³: Determinant expansion

 $\begin{aligned} & \text{FxMD} = \text{A1} \times \text{FxADC} + \text{A2} \times \text{FyADC} + \text{A3} \times \text{FzADC} + \text{A4} \times \text{MxADC} + \text{A5} \times \text{MyADC} + \text{A6} \times \text{MzADC} \\ & \text{FyMD} = \text{B1} \times \text{FxADC} + \text{B2} \times \text{FyADC} + \text{B3} \times \text{FzADC} + \text{B4} \times \text{MxADC} + \text{B5} \times \text{MyADC} + \text{B6} \times \text{MzADC} \\ & \text{FzMD} = \text{C1} \times \text{FxADC} + \text{C2} \times \text{FyADC} + \text{C3} \times \text{FzADC} + \text{C4} \times \text{MxADC} + \text{C5} \times \text{MyADC} + \text{C6} \times \text{MzADC} \\ & \text{MxMD} = \text{D1} \times \text{FxADC} + \text{D2} \times \text{FyADC} + \text{D3} \times \text{FzADC} + \text{D4} \times \text{MxADC} + \text{D5} \times \text{MyADC} + \text{D6} \times \text{MzADC} \\ & \text{MyMD} = \text{E1} \times \text{FxADC} + \text{E2} \times \text{FyADC} + \text{E3} \times \text{FzADC} + \text{E4} \times \text{MxADC} + \text{E5} \times \text{MyADC} + \text{E6} \times \text{MzADC} \\ & \text{MzMD} = \text{F1} \times \text{FxADC} + \text{F2} \times \text{FyADC} + \text{F3} \times \text{FzADC} + \text{F4} \times \text{MxADC} + \text{F5} \times \text{MyADC} + \text{F6} \times \text{MzADC} \end{aligned}$

· Matrix operation correction coefficient (A1 to F6)

Matrix operation correction coefficient is 3 bytes (24 bits). A negative number is expressed by 2's complement.

Table 3 Example of matrix operation correction coefficient

HEX.	DEC.
800000 h	-8388608
FFFFFF h	-1
000000 h	0
000001 h	1
000800 h	2048
7FFFFF h	8388607

ADC data (FxADC to MzADC)

ADC data is 3 bytes (24 bits). A negative number is expressed by 2's complement.

Table 4 Example of ADC data output

HEX.	DEC.
800000 h	-8388608
FF63C0 h	-40000
FFFFFF h	-1
000000 h	0
000001 h	1
009C40 h	40000
7FFFFF h	8388607

Matrix operation data (FxMD to MzMD)

According to calculations, the range of the matrix operation data is 6 bytes (48 bits). For the data measured at the load capacity or less, the range is 4 bytes (32 bits) at the maximum. The matrix operation data uses negative numbers expressed by 2's complement.

Table 5 Example of matrix operation data – force output

l able 5 Example of matrix operation data – force output						
Matrix operation	Matrix ope	Force				
data		ift by 11 bits	[N]			
HEX.	HEX.	DEC.	[IA]			
E7960000 h						
ζ	FFFCF2C0 h	-200000	-200.000			
E79607FF h						
FB1E0000 h						
ζ	FFFF63C0 h	-40000	-40.000			
FB1E07FF h						
FFFFF800 h						
ζ	FFFFFFF h	-1	-0.001			
FFFFFFF h						
00000000 h						
ζ	00000000 h	0	0.000			
000007FF h						
00000800 h						
ζ	00000001 h	1	0.001			
00000FFF h						
04E20000 h						
5	00009C40 h	40000	40.000			
04E207FF h						
186A07FF h						
5	00030D40 h	200000	200.000			
186A0000 h						

Table 6 Example of matrix operation data - moment output

Matrix operation Matrix operation data				
data	· ·	Moment		
HEX.	After right-shift by 11 bits HEX. DEC.		[N·m]	
EA070000 h	IIL/\.	DLC.		
2 LA070000 11	FFFD40E0 h	-180000	-1.80000	
	FFFD40E0 II	-100000	-1.00000	
EA0707FF h				
FB1E0000 h				
ζ	FFFF63C0 h	-40000	-0.40000	
FB1E07FF h				
FFFFF800 h				
5	FFFFFFF h	-1	-0.00001	
FFFFFFF h				
00000000 h				
5	00000000 h	0	0.00000	
000007FF h				
00000800 h				
5	00000001 h	1	0.00001	
00000FFF h				
04E20000 h				
5	00009C40 h	40000	0.40000	
04E207FF h			_	
15F907FF h				
ζ	0002BF20 h	180000	1.80000	
15F90000 h				

Measurement finish instruction

Each AFE completes AD conversion and ends measurement when receiving Reset command or Shutdown command. For command code and format, refer to "<u>COMMAND CODE</u>" and "<u>SPI format</u>". Fig. 12 schematically shows an example of measurement finish instruction issued to AFE1. Measurement finish instruction must be issued to all AFEs.

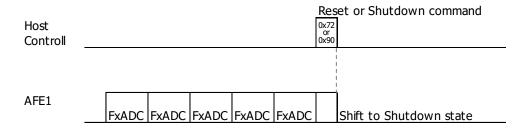


Fig. 12 Schematic of measurement finish instruction

Update of temperature sensor value for offset temperature correction

After AD conversion starts, the second and subsequent ADC data are subject to offset temperature correction using temperature sensor values acquired during the first AD conversion. This makes correction error larger with changes in ambient temperature, requiring regular update of the temperature sensor values.

Write Register command is used to update temperature sensor values for offset temperature correction. Fig. 13 schematically shows an example of the update of such data in AFE1. By executing Write Register command and writing data 0x01 to register address 0x3F at any timing, on-going AD conversion is completed, AD conversion of the temperature sensor is done again, and the data is updated. For command code and format, refer to "COMMAND CODE" and "SPI format".

The last ADC data can also be acquired during update of the temperature sensor values.

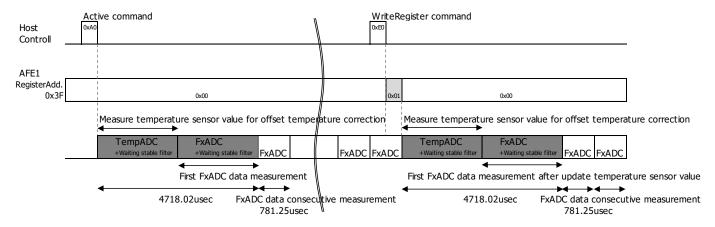
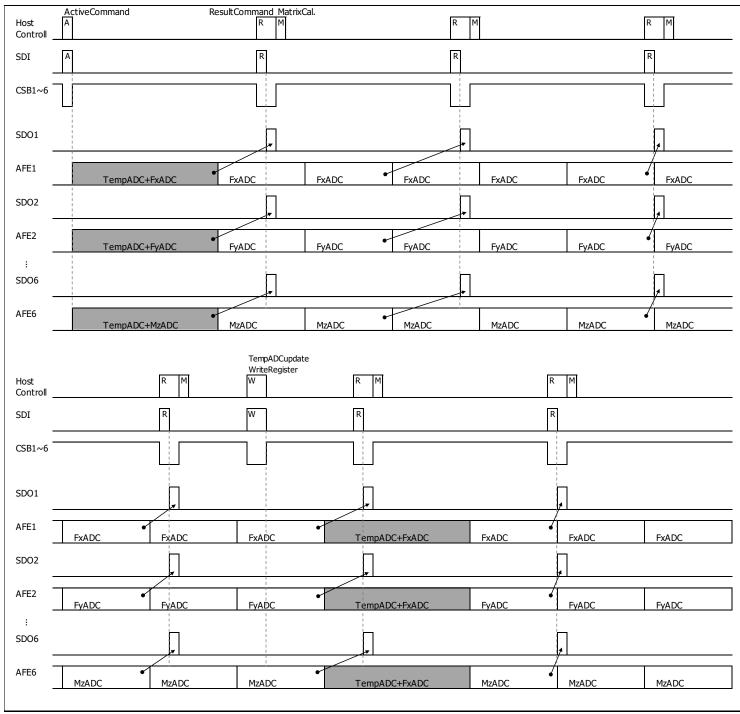
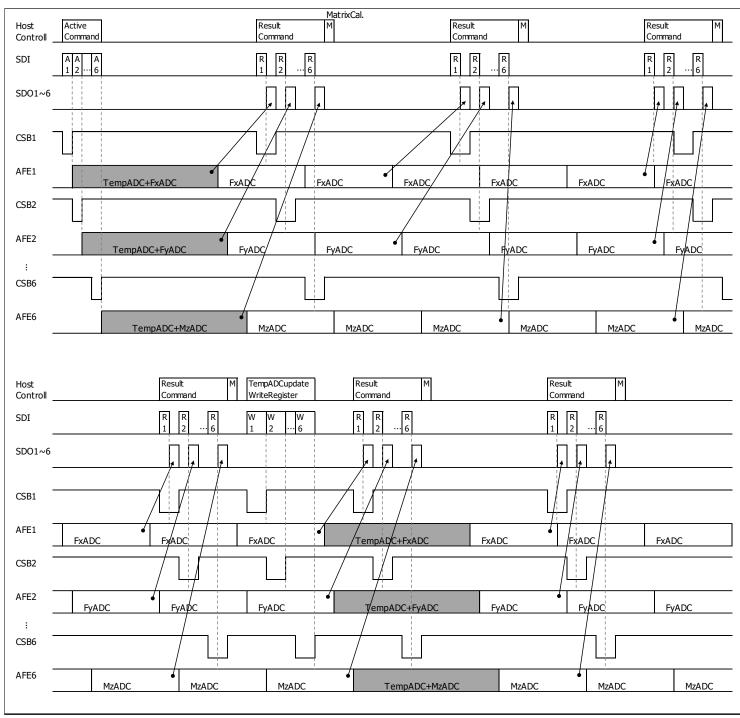


Fig. 13 Schematic of update of temperature sensor values for offset temperature correction

Measurement timing chart



*AD conversion cycle depends on AFE because internal clock is different from each AFE. Fig. 14 Integrated CSB pin - Measurement timing chart



*AD conversion cycle depends on AFE because internal clock is different from each AFE.

Fig. 15 Integrated SDO pin - Measurement timing chart

COMMAND CODE

Table 7 Command code list

Table / Command code list										
	Command Code								-	
Command Name	HEX.	BIN.						Format		
		C7	C6	C5	C4	C3	C2	C1	C0	
	0x72	0	1	1	1	0	0	1	0	SPI Write format
Reset	Reset and Return to Shutdown state. It becomes busy for the maximum 1.8msec.									
	Operation only with command code.									
Shutdown	0x90	1	0	0	1	0	0	0	0	SPI Write format
Shataown	Shift to Shutdown state. Operation only with command code.									
	0x94	1	0	0	1	0	1	0	0	SPI Write format
Idle		up the i	nternal	circuit	and pu		he Idle	state.		
					and cod		1		1	
	0xA0	1	0	1	0	0	0	0	0	SPI Write format
Active		AD conv								
					and cod		0	0	0	CDI Wisto /Dood former
	0xC0	1	1	0	0	0 + MC	0 P first	0	0	SPI Write/Read format
	ADC data (3 bytes /24 bits) is output MSB first. A negative number is expressed by 2's complement.									
Read ADC Result	For output range, positive output is 000000 h to 7FFFFF h (0 to +8388607 in decimal number),									
	while negative output is FFFFFF h to 800000 h (-1 to -8388608 in decimal number).									
	However, the measurement data acquired during the usage beyond the recommended operating conditions cannot be guaranteed.									
	0xC2	1	1	0	0	0	0	1	0	SPIWrite/Read format
		ADC data (3 bytes /24 bits) is output MSB first.								
	A nega	ative nu	ımber i	s expre	essed by	/ 2's co	omplem			
										to +8388607 in decimal number),
	while negative output is FFFFFF h to 800000 h (-1 to -8388608 in decimal number). However, the measurement data acquired during the usage beyond the recommended operating									
Read Temperature	conditions cannot be guaranteed.									
ADC Result	Tempe	erature	value['	℃] = [℃	EC./2^	16				
	Output	exampl								
	0000	201010	BIN.	00000	2000 6	HE		DEC		F 000°C
	I -	0010100 1100100					000 h	3276 1638 ²		5.000°C 25.000°C
	l -	0110100					000 h	2949:		45.000°C
Write Register	0xE0	1	1	1	0	0	0	0	0	SPI Write format
	It is used for writing date to resister.									
	After s						e order	of mer	mory a	ddress of 8 bits and write data of 8
	bits. After transmitting command code,									
Read NVM	0xD6	ransmii 1	tting co	omman 0	a coae, 1	0	1	1	0	SPI Write/Read format (Busy)
		_	_	Ū						
	It is used for reading matrix operation correction coefficients.									

STATE TRANSITION DIAGRAM

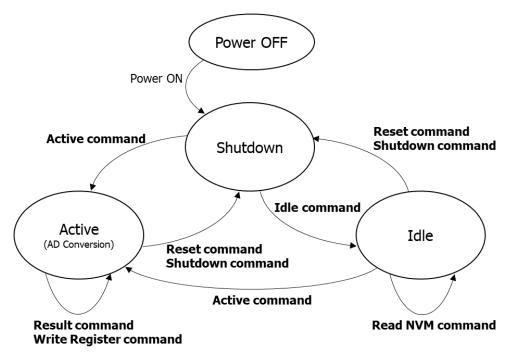


Fig. 16 State transition diagram

Table 8 State transition table

State Command	Shutdown	Active	Idle	
Reset	Power on Reset & Initial Boot =>Shutdown state	Power on Reset & Initial Boot =>Shutdown state	Power on Reset & Initial Boot =>Shutdown state	
Shutdown	=>Keep state	=>Shutdown state	=>Shutdown state	
Active	Reset & Boot Load =>Active state (AD conversion)	Ignore(note ⁵) =>Keep state	=>Active state (AD conversion)	
Result	Ignore(note ⁵) =>Keep state	Output result =>Keep state	Do not issue(note ⁶) =>Keep state	
Idle	Reset & Boot Load =>Idle state	Do not issue(note ⁷) =>Idle state	=>Keep state	
Write Register	Ignore(note ⁵) =>Keep state	Temperature ADC update =>Keep state	Do not issue(note ⁸) =>Keep state	
Read NVM	Ignore(note ⁵) =>Keep state	Do not issue(note ⁷) =>Keep state	Output Matrix coeff. =>Keep state	

note⁵: NACK is returned to the command.

note⁶: The correct result is not output. Additionally, ACK is returned to the command.

note⁷: Although command is acceptable, it goes unintended behavior since sequence is running.

note⁸: Although command is acceptable, it goes unintended behavior during sequence execution.

SERIAL INTERFACE

It supports SPI as an interface for serial communication.

Tab	و ما	Baud	rate
I GD		Dauu	Tate

Items	Symbol	Condition	Min.	Тур.	Max.	Unit.	
SPI communication speed	BR _{SPI1}	VDDIO ≥ 2.0 V Cb ≤ 100 pF	1	-	5.0		
	BR _{SPI2}	VDDIO < 2.0V Cb < 100pF	-	-	1.0	Mbps	
	BR _{SPI3}	$ \begin{array}{c} \text{VDDIO} \geqq 2.0 \text{V} \\ \text{Cb} \leqq 400 \text{pF} \end{array} $	-	-	2.5	Μυρς	
	BR _{SPI4}	VDDIO < 2.0V Cb < 100pF	-	-	0.5		

SPI format

The basic format of SPI is shown below. The relationship between clock(SCLK) and data(SDI/SDO) is Mode3. Data send/receive is started when CSB becomes low level from the status when SCLK is high level. Data is updated on falling edges of the SCLK, and sampled on rising edges of the SCLK. Data send/receive is ended when CSB becomes high level from the status when SCLK is high level.

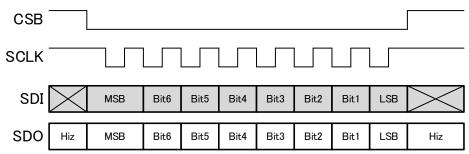


Fig. 17 SPI Waveform

SPI Write format

Please send command code of 8 bits. When the command is received, it turns over ACK to 8 bits. If there is data, please continue sending.



Fig. 18 SPI Write format

SPI Write/Read format

Please send command code of 8 bits. When the command is received, it turns over ACK to 8 bits and it outputs the data MSB first.

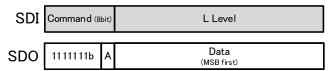


Fig. 19 SPI Write/Read format

SPI Write/Read format (Busy)

Please send command code of 8 bits. When their commands are received, it turns over ACK to 8 bits. Then, please send memory address of 8 bits. After receiving the memory address, the internal area becomes busy for 25usec at the maximum in order to prepare for data transmission. During this time, it returns 0x00 which indicates busy state. When data preparation is completed, it outputs 0x01, followed by data of 8 bits.

How to discern busy state:

Please continue clock input in the same communication status after transmitting the write data. Then, it returns 0x00 which indicates busy status. It returns 0x01 when writing is completed.

* 0x00 to indicate busy may sometimes be output or not depending on the clock frequency.



Fig. 20 SPI Write/Read format (Busy)

SPI ACK

When command code which is send in each SPI format is received, it outputs L level to 8 bits as ACK. If command code is not accepted or command code is not valid, it outputs H level to 8 bits as NACK.

SPI AC Characteristics

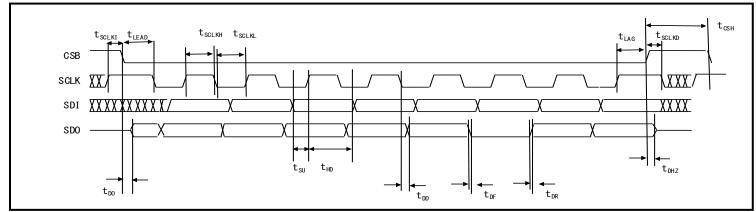


Fig. 21 SPI AC timing chart

Table 10 SPI AC Characteristics

Items	Symbol	VDDI	O<2V	VDDIO≧2V		Unit.
items	Зуппоот	min.	max.	min.	max.	Offic.
SCLK frequency(Duty 50±10%)	fsclk	-	1	-	5	MHz
SCLK High period (90%~90%)	t sclkh	400	-	80	1	ns
SCLK Low period(10%~10%)	t _{SCLKL}	400	-	80	-	ns
SCLK wait time	tsclki	500	-	100	1	ns
SCLK Delay time	t _{SCLKD}	0	-	0	1	ns
CSB High period(90%~90%)	tсsн	1000	-	200	1	ns
Time from CSB falling to SCLK falling	t _{LEAD}	0	-	0	-	ns
Time from SCLK rising to CSB rising	t _{LAG}	500	-	100	-	ns
SDI setup time	t su	100	-	10	-	ns
SDI hold time	t _{HD}	10	-	10	-	ns
SDO rise time(Load 100pF) (10%~90%)	t _{DR}	-	50	1	50	ns
SDO fall time(Load 100pF) (10%~90%)	t _{DF}	-	50	1	50	ns
SDO output delay time (Load 100pF)	t _{DD}	-	120	1	60	ns
SDO output delay time from CSB falling (Load 100pF)	t _{DO}	-	120	-	60	ns
Time from CSB rising to SDO output HiZ (Load 100pF)	t _{DHZ}	-	170	-	170	ns

TYPICAL APPLICATION CIRCUIT

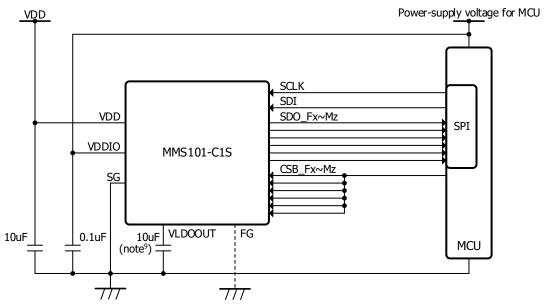


Fig. 22 Integrated CSB pin – Example application circuit

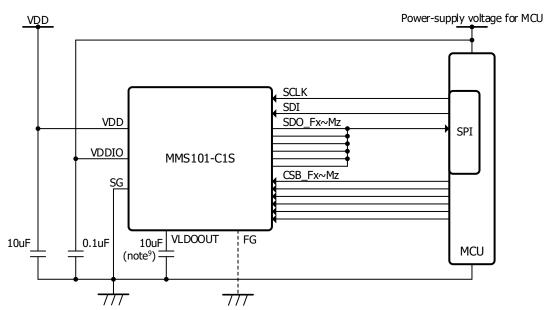


Fig. 23 Integrated SDO pin – Example application circuit

note⁹: It is recommended to be placed as close as possible for noise reduction.

DIMENSIONS

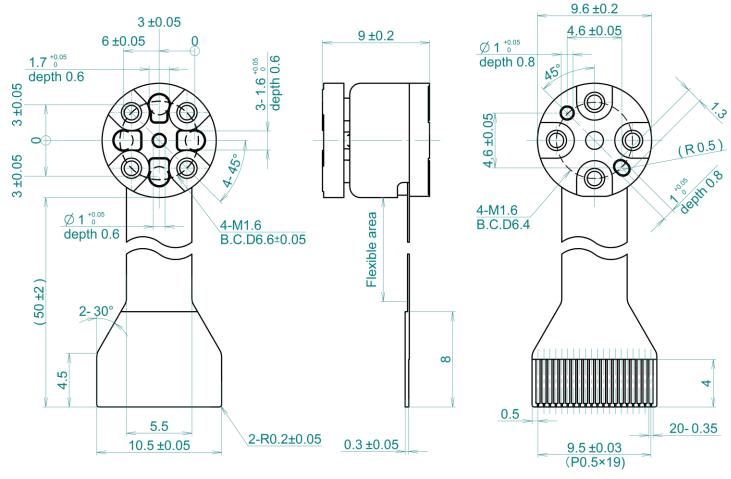


Fig. 24 Dimensions

- Recommended FPC connector
- FH52K-20S-0.5SH (HIROSE ELECTRIC CO.,LTD)
- FH28D-20S-0.5SH (HIROSE ELECTRIC CO.,LTD)
- · 046288020600846+ (KYOCERA Corporation)

Sensor coordination systems

*The origin is the sensor top surface center.

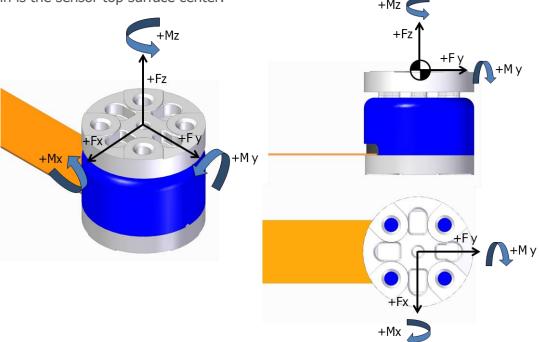


Fig. 25 Sensor coordination systems

Example of sensor attachment

It is important to minimize the attachment deformation during load application not to affect the sensor output. Therefore, the attachment should be designed to be hardly deformed by the load assumed in the normal use, using highly rigid materials such as SUS.

Fig. 26, 27 and 28 show examples of top & bottom side shape and installation of the attachment.

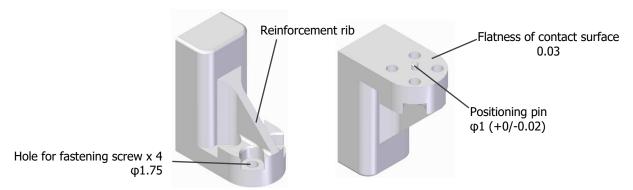


Fig. 26 Example of top side attachment

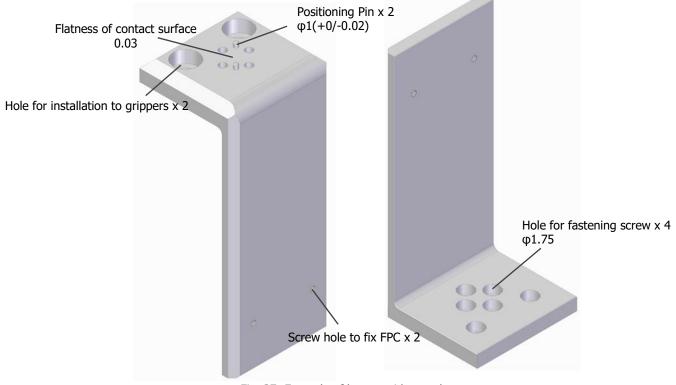
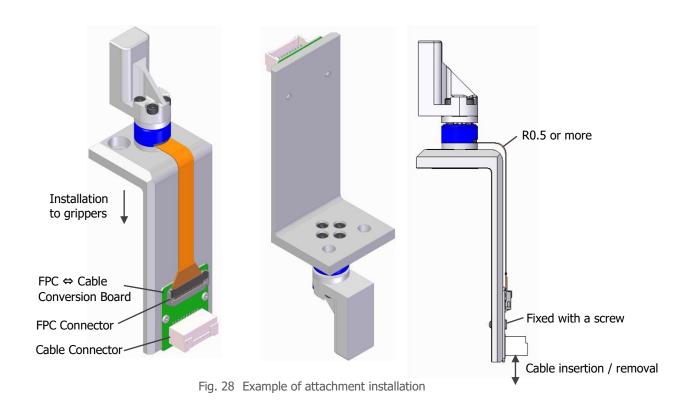


Fig. 27 Example of bottom side attachment



It is recommended to fix the board connected to FPC to the attachment with a screw so that the FPC is not bent repeatedly. Additionally, cables should be inserted and removed with the FPC fixed to the attachment with a screw to minimize load to the FPC.

Fig. 26, 27 and 28 show examples. The attachment should be designed depending on the intended use.

PRECAUTIONS FOR SENSOR INSTALLATION

This product is a precision measuring instrument. Therefore, it needs to be installed following the appropriate procedure to avoid overload to it. Failure to observe the recommendations included in this manual may cause damage to the sensor.

Installation screw

Four M1.6 screws should be used for installation on both top and bottom surfaces. **Length of the screws inserted in the installation holes of both surfaces should be 1.7 mm or shorter.** The tapped holes are 1.8 mm (min. 1.7 mm) through holes. Inserting a screw over 1.7 mm long could damage parts in the sensor.

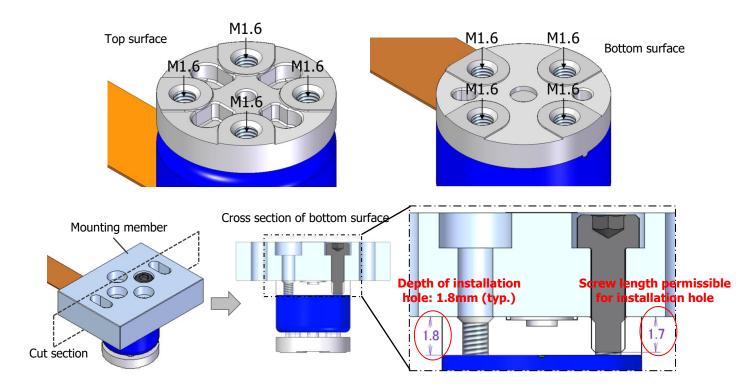


Fig. 29 Precautions for instllation screw

Positioning hole

For the top surface, a $\phi1$ round hole in the middle, a $\phi1.7$ round hole, or 1.6 x 1.45 mm square holes can be used for positioning. For the bottom surface, a $\phi1$ round hole and a $\phi1$ slotted hole can be used for positioning. For details, refer to "DIMENSIONS".

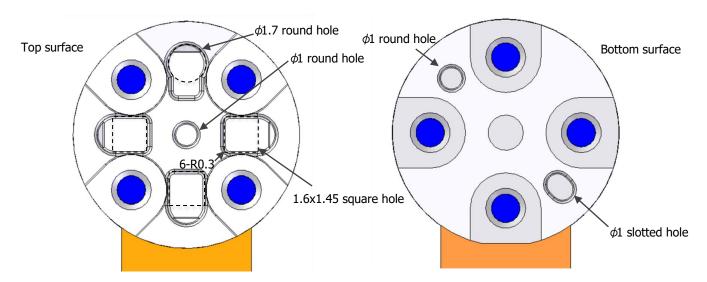
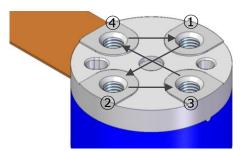


Fig. 30 Positioning holes

Recommended tightening method of sensor installation screw

The recommended tightening torque is 0.15N·m for M1.6 screws used to install this sensor. **DO NOT fasten one screw tightly at first step**, or the sensor may detect incorrect force and moment. In the worst case, the sensor could be damaged.

Screws must be fastened in the diagonal order as shown below. **First, they should be lightly fastened,** and then, fastened in more than 2 steps with the recommended tightening torque.



Ex. 1st round ①0.05N·m
$$\rightarrow$$
 ②0.05N·m \rightarrow ③0.05N·m \rightarrow ④0.05N·m \rightarrow 2nd round ①0.15N·m \rightarrow ②0.15N·m \rightarrow ③0.15N·m \rightarrow ④0.15N·m

Fig. 31 Example of screw tightening order

Sensor contact surface

Flatness of the sensor side contact surface is 0.03mm, and the installation side contact surface should be designed at the same flatness. Level difference resulting from poor flatness could cause the force and the moment to be detected incorrectly. In the worst case, the sensor could be damaged. The installation side contact surface needs to be rigid enough against loads.

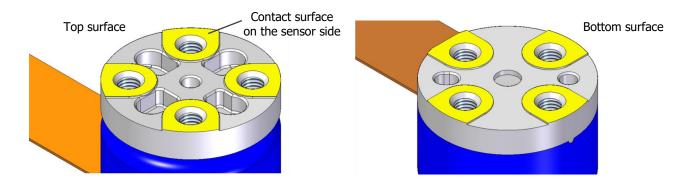


Fig. 32 Sensor side contact surface

PRECAUTIONS FOR SENSOR HANDLE

This product is a precision measuring instrument. Therefore, it needs to be handled following the appropriate procedure to avoid overload to it. Failure to observe the recommendations included in this manual may cause damage to the sensor.

Handling of sensor FPC

The FPC must NOT be strongly pulled in a lateral or the upper direction while the sensor body is fixed with screws. Otherwise, load is applied to the base of the FPC, and the wiring on the FPC might be snapped.

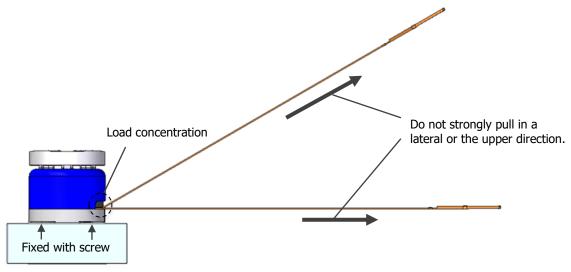


Fig. 33 Precaution for handling of sensor FPC - 1

In the FPC termination part, a level difference exists between the FPC and the reinforcing plate. Bending the FPC at this level difference part could cut the wiring on the FPC.

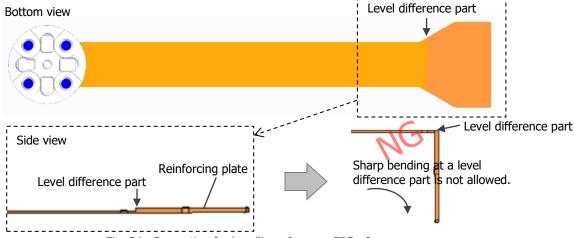


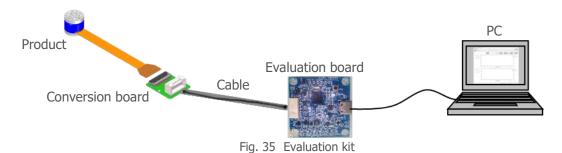
Fig. 34 Precaution for handling of sensor FPC - 2

OPTION

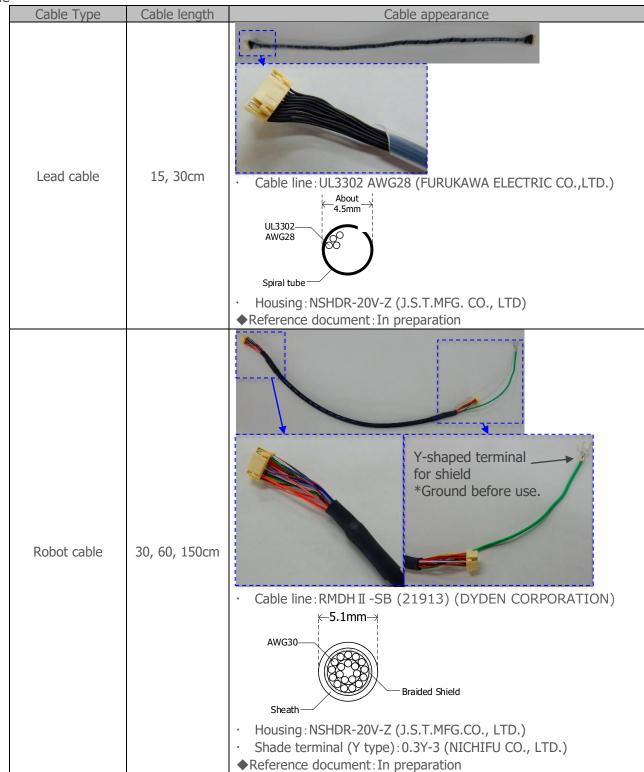
As options, evaluation kit and conversion board are available. Please order if necessary. However, the options are guaranteed only for checking the operation at the time of shipment, and will only be provided for sample support. Please note.

Evaluation Kit

Using evaluation kit with PC applications allows logging data to be acquired. In addition to product to which conversion board for evaluation kit are connected, they consist of cables and evaluation board. Several types of cables and evaluation boards are available. Select them according to the application.



Cable



Evaluation Board

Table 11 Evaluation Board line-up

			No. of	on Board line-up
Board Name	External Communication	Power Supply	connectable	Board appearance
ForceSensor ControllerBoard Ver2.0	USB	USB	Max. 1 pcs	40mm 40mm 40mm 6.1mm • Conversion Board side connector : SM20B-NSHDZS (J.S.T.MFG. CO., LTD) • External communication side connector : CAM-L05-024-050-ACGAA (MITSUMI ELECTRIC CO., LTD) ♦ Reference document: In preparation
ForceSensor MultiFingerBoard Ver1.0	Ethernet	DC Jack	Max. 5 pcs	70mm 1.0mm 1.0mm 1.0mm 13.61mm Conversion Board side connector :SM20B-NSHDZS (J.S.T.MFG. CO., LTD.) External communication side connector :J3011G21DNLT (Pulse Electronics CO., LTD.) DC jack:M04-730A0 (MARUSHIN ELECTRIC MFG. CO., LTD) Reference document:In preparation

Conversion Board

Conversion Board is intended to connect a cable to this product. Connect the product terminal to the FPC connector and convert it to a cable connector with the number of pins according to the application.

Table 12 Conversion board line-up

Table 12 Conversion board line-up								
Board Name	Terminal co	nversion table	Board appearance					
Conv. BD Ver1.0 (For Evaluation Kit)	MMS101 Conv.BD Output Output VDD VDD VDDIO VDDIO VLDOOUT VLDOOUT SG SG FG FG FG FG N.C. SCLK SCLK SDI SDI CSB_Fx CSB_Fx CSB_Fy CSB_Fy	Opin MMS101 Conv.BD Output CSB_Fz CSB_Fz CSB_Mx CSB_Mx CSB_My CSB_My CSB_Mz CSB_Mz SDO_Fx SDO_Fx SDO_Fy SDO_Fy SDO_Fz SDO_Fz SDO_Mx SDO_Mx SDO_My SDO_My SDO_Mz SDO_Mz	0.5mm					
Conv. BD Ver2.0	12pin(Integ MMS101 Output Conv.BD Output VDD VDD VDDIO VDDIO VLDOOUT - SG SG FG - SCLK SCLK SDI SDI CSB_Fx CSB CSB_Fy CSB	rated CSB pin) MMS101 Output CSB_Fz CSB_Mx CSB_My CSB_Mz SDO_Fx SDO_Fx SDO_Fy SDO_Fy SDO_Fz SDO_Mx SDO_My SDO_My SDO_Mz SDO_Mz SDO_Mz SDO_Mz	Appearance undecided, In preparation ◆Reference document: In preparation					
Conv. BD Ver2.1	12pin(Integral MMS101 Conv.BD Output Output VDD VDD VDDIO VDDIO VLDOOUT - SG SG FG - SCLK SCLK SDI SDI CSB_Fx CSB_Fx CSB_Fy CSB_Fy	ated SDO pin) MMS101 Output CSB_Fz CSB_Fz CSB_Mx CSB_Mx CSB_My CSB_My CSB_Mz SDO_Fx SDO_Fy SDO_Mx SDO_My SDO_Mz	Appearance undecided, In preparation ◆ Reference document: In preparation					

MITSUMI ELECTRIC CO.,LTD.

Strategy Engineering Department Semiconductor Business Division

Tel: +81-46-230-3470 / http://www.mitsumi.co.jp

Notes:

Any products mentioned this datasheet are subject to any modification in their appearance and others for improvements without prior notification. The details listed here are not a guarantee of the individual products at the time of ordering. When using the products, you will be asked to check their specifications.